## High-resolution visualization of the anomalous Nernst effect using AFM tip-induced local temperature gradients

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We have developed a novel method to visualize the anomalous Nernst effect (ANE) using an atomic force microscope (AFM) [1, 2]. In this method, a local temperature gradient is created by contacting an AFM probe with a heated sample wire, as shown in Fig. 1. We detect the voltage resulting from ANE at both ends of the sample wire, enabling magnetic imaging with a spatial resolution of ~80 nm. This method was applied to the antiferromagnetic Weyl semimetal Mn<sub>3</sub>Sn. Figure 2 presents the results for Kagome-in-plane textured polycrystalline Mn<sub>3</sub>Sn [3]. As seen in Figs. 2(b) and 2(c), the local ANE, corresponding to the distribution of the cluster magnetic octupoles in Mn<sub>3</sub>Sn, was observed in both the initial and residual states. Furthermore, this method is applicable to a wide range of other materials and devices. In this presentation, we will report on these results and demonstrate the high versatility of the method.

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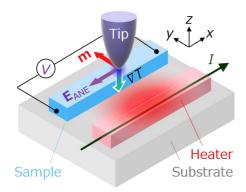


Fig. 1: Schematic diagram of the anomalous Nernst effect mapping.

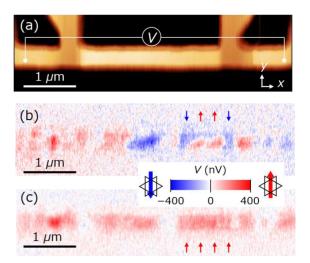


Fig. 2: Results on a Mn<sub>3</sub>Sn nanowire. (a) Topography. (b), (c) Results of the anomalous Nernst voltage mapping in the initial and residual states, respectively.

- [1] N. Budai et al. Appl. Phys. Lett. 122, 102401 (2023)
- [2] H. Isshiki et al. Front. Phys., 11 (2023)
- [3] H. Isshiki et al. Phys. Rev. Lett. 132, 216702 (2024)